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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/806,457	06/14/2001	Christian Caspersen	2836-0153PUS1	1421	
2292 BIRCH STEW	7590 07/22/200 'ART KOLASCH & BI	EXAM	EXAMINER		
PO BOX 747			LEE, SHUN K		
FALLS CHUI	RCH, VA 22040-0747		ART UNIT	PAPER NUMBER	
			2884		
			NOTIFICATION DATE	DELIVERY MODE	
			07/22/2009	ELECTRONIC	

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

mailroom@bskb.com

Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)	
09/806,457	CASPERSEN, CHRISTIAN	
Examiner	Art Unit	
Shun Lee	2884	

	Ondir Ecc	2004	
The MAILING DATE of this communication appe	ars on the cover sheet with the d	orrespondence add	ress
THE REPLY FILED 10 July 2009 FAILS TO PLACE THIS APPL	ICATION IN CONDITION FOR AL	LOWANCE.	
 X The reply was filed after a final rejection, but prior to or on application, applicant must timely file one of the following i application in condition for allowance; (2) a Notice of Appe for Continued Examination (RCE) in compliance with 37 C periods: 	eplies: (1) an amendment, affidavi	t, or other evidence, w with 37 CFR 41.31; or	hich places the (3) a Request
 a) The period for reply expires 4 months from the mailing date 	of the final rejection.		
 The period for reply expires on: (1) the mailing date of this Ar no event, however, will the statutory period for reply expire la Examiner Note: If box 1 is checked, check either box (a) or (I 	dvisory Action, or (2) the date set forth in ter than SIX MONTHS from the mailing b). ONLY CHECK BOX (b) WHEN THE	date of the final rejection	n.
MONTHS OF THE FINAL REJECTION. See MPEP 706.07(I Extensions of time may be obtained under 37 CFR 1,136(a). The date have been filed is the date for purposes of determining the period of exten- under 37 CFR 1,17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office later may reduce any earmed patent term adjustment. See 37 CFR 1,704(b).	on which the petition under 37 CFR 1.1: ension and the corresponding amount of hortened statutory period for reply origi	of the fee. The appropria nally set in the final Offic	te extension fee e action; or (2) as
NOTICE OF APPEAL			
 The Notice of Appeal was filed on A brief in compl filing the Notice of Appeal (37 CFR 41.37(a)), or any exter Notice of Appeal has been filed, any reply must be filed wi AMENDMENTS 	sion thereof (37 CFR 41.37(e)), to	avoid dismissal of the	
The proposed amendment(s) filed after a final rejection, b	us prior to the date of filing a brief	will not be entered be	
(a) ☐ They raise new issues that would require further cor (b) ☐ They raise the issue of new matter (see NOTE belov	sideration and/or search (see NOT		cause
 (c) They are not deemed to place the application in bett appeal; and/or 	er form for appeal by materially rec	lucing or simplifying th	ne issues for
(d) ☐ They present additional claims without canceling a c NOTE: (See 37 CFR 1.116 and 41.33(a)).	orresponding number of finally reje	cted claims.	
4. The amendments are not in compliance with 37 CFR 1.12	1. See attached Notice of Non-Cor	mpliant Amendment (F	PTOL-324).
 Applicant's reply has overcome the following rejection(s): 			
 Newly proposed or amended claim(s) would be all non-allowable claim(s). 	owable if submitted in a separate, t	•	
 For purposes of appeal, the proposed amendment(s): a) [how the new or amended claims would be rejected is prov The status of the claim(s) is (or will be) as follows: 		be entered and an ex	planation of
Claim(s) allowed:			
Claim(s) objected to:			
Claim(s) rejected: 1,7,9,11,12,15,16,23,24,27,29,36,37,44	and 47-51.		
Claim(s) withdrawn from consideration: AFFIDAVIT OR OTHER EVIDENCE			
8. ☑ The affidavit or other evidence filed after a final action, but	hafara as an the data of filing a Nic	tion of Annual will not	he entered
 because applicant failed to provide a showing of good and was not earlier presented. See 37 CFR 1.116(e). 			
 The affidavit or other evidence filed after the date of filing an entered because the affidavit or other evidence failed to or showing a good and sufficient reasons why it is necessary 	vercome <u>all</u> rejections under appea and was not earlier presented. Se	l and/or appellant fails e 37 CFR 41.33(d)(1)	s to provide a
 The affidavit or other evidence is entered. An explanation REQUEST FOR RECONSIDERATION/OTHER 	of the status of the claims after er	ntry is below or attache	ed.
 The request for reconsideration has been considered but <u>See Continuation Sheet.</u> 	does NOT place the application in	condition for allowand	ce because:
 Note the attached Information Disclosure Statement(s). (Other: 	PTO/SB/08) Paper No(s)		
/David P. Porta/ Supervisory Patent Examiner, Art Unit 2884			

Continuation of 11, does NOT place the application in condition for allowance because: applicant argues that the principle of operation in Malin et al. teach away from the claimed invention because a dark field stop restricts any possible detection of fluorescence. Examiner respectfully disagrees. First, applicant's arguments based on a transmission geometry (see Figs. on pg. 12 of remarks filed 10 July 2009) are inapplicable to the reflection geometry of Malin et al. (see Figs. 1 and 2 of Malin et al.). Second, it is important to recognize that the dark field stop assembly (18 in Figs. 1 and 4c) of Malin et al. do not block the excitation beam (1 in Figs. 1 and 4c). Thus applicant's arguments of darkfield illumination (wherein a stop is used to block a portion of the excitation beam) are also inapplicable to Malin et al. since Malin et al. teach a dark field stop assembly that is used to block a portion of the light from the sample. Further, applicant's arguments rest on the unsupported assumption that the dark field stop of Malin et al. must have such a large size so as to restrict any possible detection of fluorescence. On the contrary, the dark field stop of Malin et al. is as small as possible since Malin et al. state (column 7, lines 10-14) that "to allow the passage of diffused light close to the optical axis, that proportion of the diffused-light cone 14 effectively blocked by the dark-field stop 61 must be as small as possible". Thus Malin et al. teach that the proportion of collection angle effectively blocked by the stop is as small as possible. Further, Hamashima et al. teach (column 4, lines 47-59) to provide a dichroic mirror (24 in Fig. 1) for simultaneously detecting three kinds of light information (i.e., the scattered light from the edge of the pattern, the reflection from the pattern and the fluorescence or phosphorescence from the pattern) so that by using these three kinds of light information and the scanning position information of the beam spot, the desired edge detection, pattern position detection and line width and dimension measurement of the different patterns (e.g., the photoresist pattern and the polysilicon pattern) are performed in a diversified manner. Thus it would have been obvious to one having ordinary skill in the art at the time of the invention to provide a dichroic mirror in the apparatus of Malin et al., in order to obtain fluorescence measurements in addition to scattering measurements at a desired resolution so as to determine defects and contamination in a diversified manner. Therefore, applicant's arguments are not persuasive.